

Supplementary Materials: Effect of Al_2O_3 and ZrO_2 Filler Material on the Microstructural, Thermal and Dielectric Properties of Borosilicate Glass-Ceramics

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Table S1. PDF card numbers and their corresponding crystal structures.

PDF card number	Chemical formula	Mineral name	Crystal structure
9007635	Al_2O_3	Corundum	Hexagonal
9006525	$\text{Al}_2\text{O}_5\text{Si}$	Silimanite	Orthorhombic
8104264	ZrO_2	-	Monoclinic
9000713	$\text{Al}_2\text{O}_5\text{Si}$	Silimanite	Orthorhombic

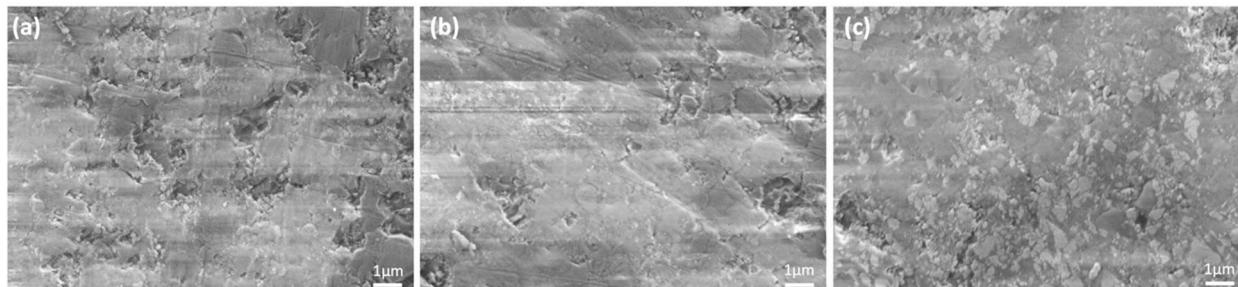


Figure S1. SEM images of sintered glass ceramics at 20.00 KX a) 30Al-O, b) 40Al-O, c)50Al-O.

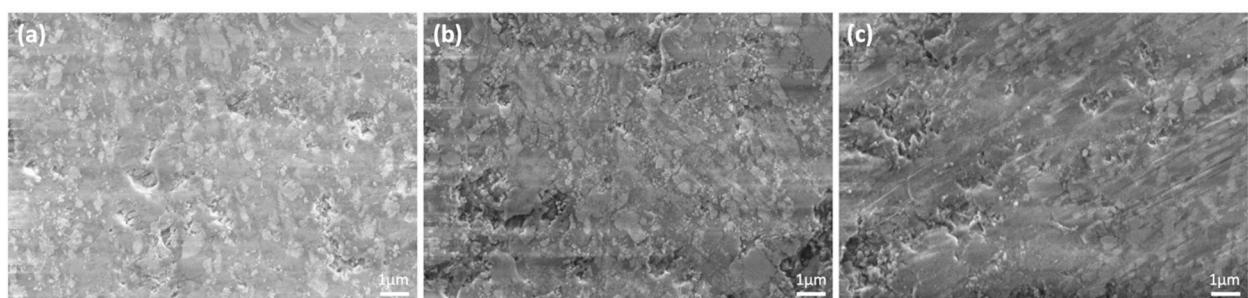


Figure S2. SEM images of sintered glass ceramics at 20.00 KX a) 30Zr-Ar, b) 40Zr-Ar, c)50Zr-Ar.

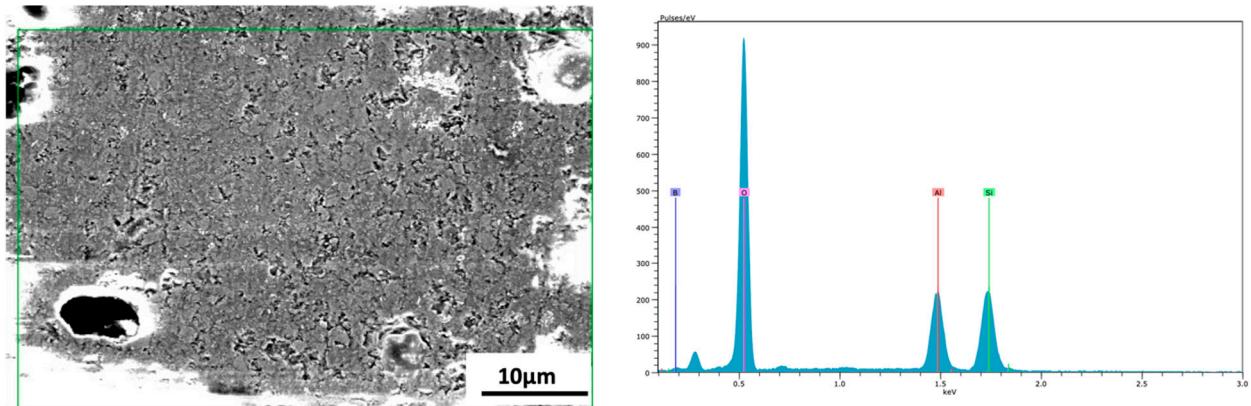


Figure S3. EDS analysis of the 30Al-O sample.

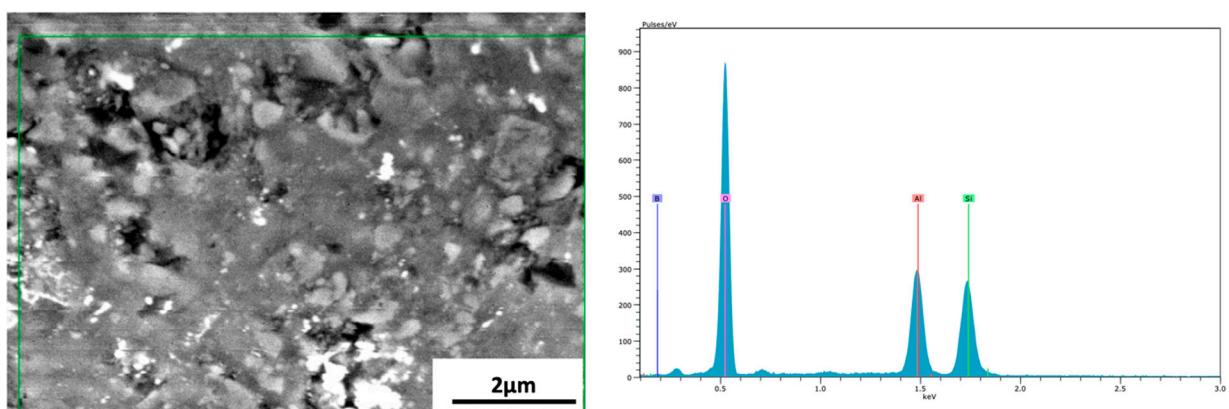


Figure S4. EDS analysis of the 40Al-O sample.

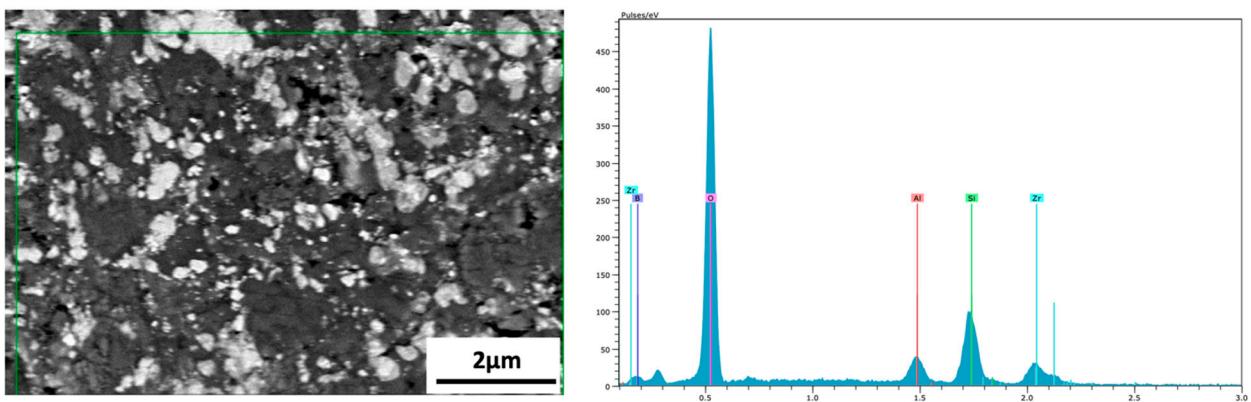


Figure S5. EDS analysis of the 30Zr-Ar sample.

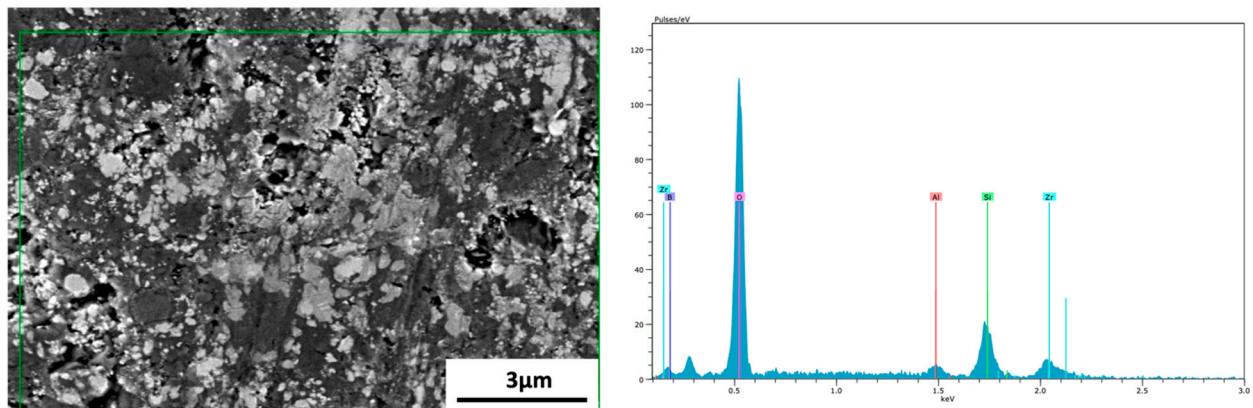


Figure S6. EDS analysis of the 40Zr-Ar sample.

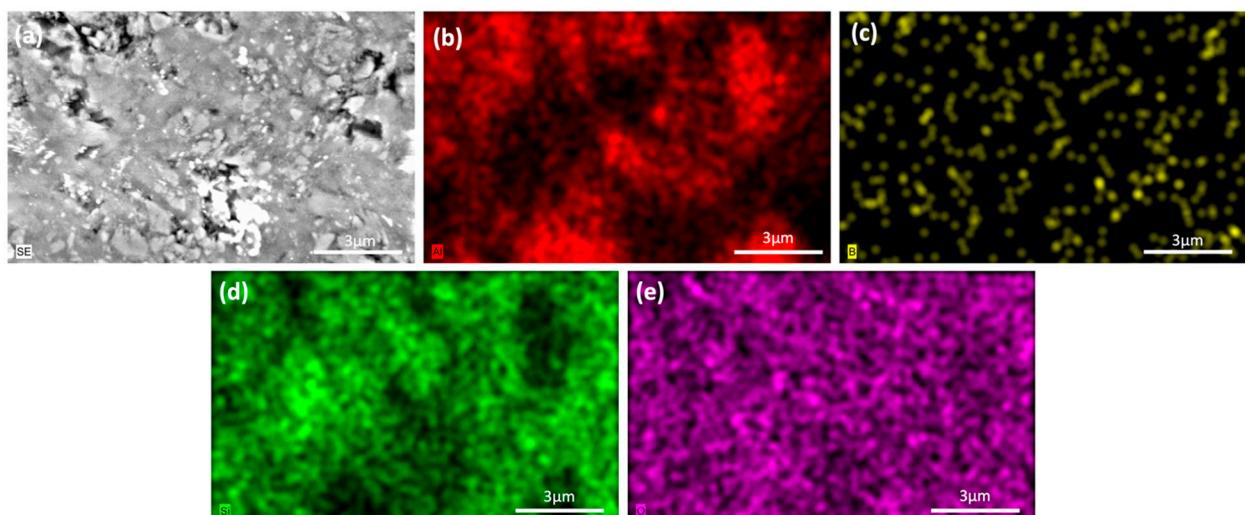


Figure S7. SEM/EDX analyses of the 40Al-O sample (a) SEM image, (b) EDX mapping of Al, (c) EDX mapping of B, (d) EDX mapping of Si, (e) EDX mapping of O.

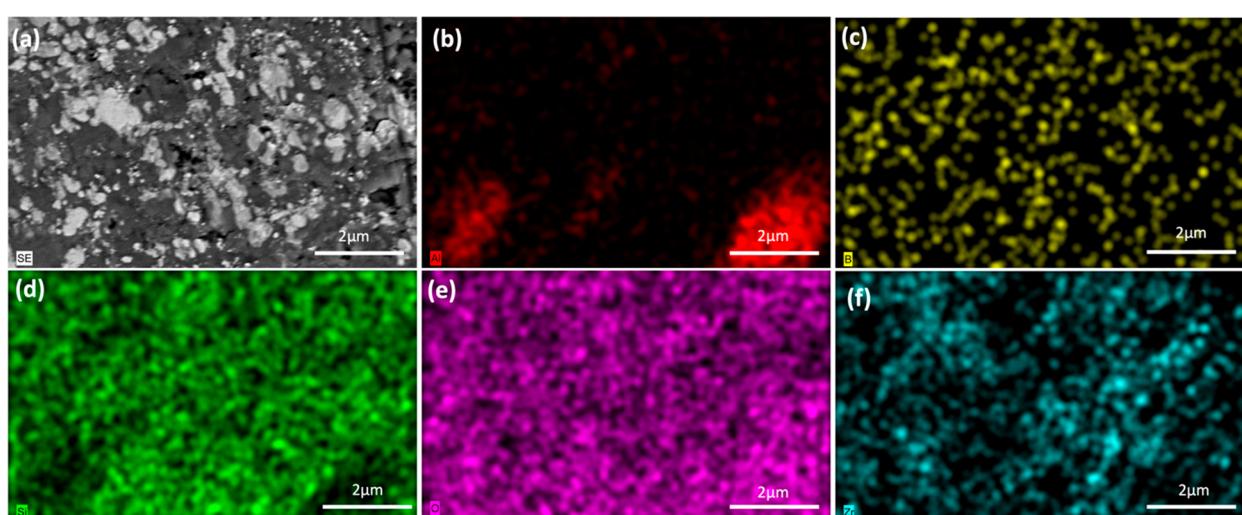


Figure S8. SEM/EDX analyses of the 30Zr-Ar sample (a) SEM image, (b) EDX mapping of Al, (c) EDX mapping of B, (d) EDX mapping of Si, (e) EDX mapping of O, (f) EDX mapping of Zr.